

32K x 18 Synchronous Cache RAM

Features

- Supports 66-MHz Pentium[™] microprocessor cache systems with zero wait states
- 32K by 18 common I/O
- Fast clock-to-output times

 8.5 ns
- Two-bit wraparound counter supporting Pentium and 486 burst sequence (CY7C178)
- Two-bit wraparound counter supporting linear burst sequence (CY7C179)
- Separate processor and controller address strobes
- Synchronous self-timed write

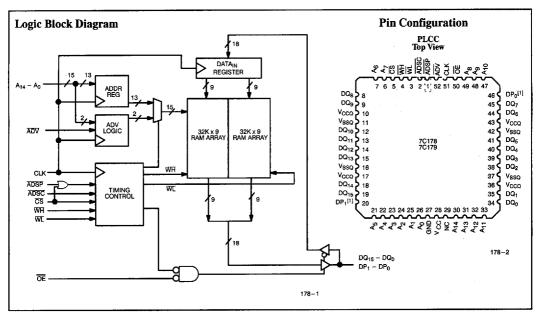
- Direct interface with the processor and external cache controller
- Asynchronous output enable
- I/Os capable of 3.3V operation
- Industry-standard pinout
- 52-pin PLCC and PQFP

Functional Description

The CY7C178 and CY7C179 are 32K by 18 synchronous cache RAMs designed to interface with high-speed microprocessors with minimum glue logic. Maximum access delay from clock rise is 8.5 ns. A 2-bit onchip counter captures the first address in a burst and increments the address automatically for the rest of the burst access.

The CY7C178 is designed for Intel Pentium and i486 CPU-based systems; its counter follows the burst sequence of the Pentium and the i486 processors. The CY7C179 is architected for processors with linear burst sequences. Burst accesses can be initiated with the processor address strobe (ADSP) or the cache controller address strobe (ADSC) inputs. Address advancement is controlled by the address advancement (ADV) input.

A synchronous self-timed write mechanism is provided to simplify the write interface. A synchronous chip select input and an asynchronous output enable input provide easy control for bank selection and output three-state control.



Selector Guide

	7C178-8 7C179-8	7C178-10 7C179-10	7C178-12 7C179-12	
Maximum Access Time (ns)		8.5	10.5	12.5
Maximum Operating Current (mA)	Commercial	225	210	180
	Military	377777		270

Shaded area contains advanced information.

Note

DP₀ and DP₁ are functionally equivalent to DQ_x.

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Functional Description (continued) Single Write Accesses Initiated by ADSP

This access is initiated when the following conditions are satisfied at clock rise: (1) \overline{CS} is LOW and (2) \overline{ADSP} is LOW, \overline{ADSP} -triggered write cycles are completed in two clock periods. The address at A_0 through A_{14} is loaded into the address register and address advancement logic and delivered to the RAM core. The write signal is ignored in this cycle because the cache tag or other external logic uses this clock period to perform address comparisons or protection checks. If the write is allowed to proceed, the write input to the CY7C178 and CY7C179 will be pulled LOW before the next clock rise. \overline{ADSP} is ignored if \overline{CS} is HIGH.

If WH, WL, or both are LOW at the next clock rise, information presented at DQ_0-DQ_{15} and DP_0-DP_1 will be written into the location specified by the address advancement logic. WL controls the writing of DQ_0-DQ_7 and DP_0 while WH controls the writing of DQ_8-DQ_{15} and DP_1 . Because the CY7C178 and CY7C179 are common-I/O devices, the output enable signal (\overline{OE}) must be deasserted before data from the CPU is delivered to DQ_0-DQ_{15} and DP_0-DP_1 . As a safety precaution, the appropriate data lines are three-stated in the cycle where WH, WL, or both are sampled LOW, regardless of the state of the \overline{OE} input.

Single Write Accesses Initiated by ADSC

This write access is initiated when the following conditions are satisfied at rising edge of the clock: (1) \overline{CS} is LOW, (2) \overline{ADSC} is LOW, and (3) \overline{WH} or \overline{WL} are LOW. \overline{ADSC} triggered accesses are completed in a single clock cycle.

The address at A_0 through A_{14} is loaded into the address register and address advancement logic and delivered to the RAM core. Information presented at $DQ_0 - DQ_{15}$ and $DP_0 - DP_1$ will be written into the location specified by the address advancement logic. Since the CY7C178 and the CY7C179 are common-I/O devices, the output enable signal (\overline{OE}) must be deasserted before data from the cache controller is delivered to the data and parity lines. As a safety precaution, the appropriate data and parity lines are three-stated in the cycle where \overline{WH} and \overline{WL} are sampled LOW regardless of the state of the \overline{OE} input.

Single Read Accesses

A single read access is initiated when the following conditions are satisfied at clock rise: (1) CS is LOW, (2) ADSP or ADSC is LOW,

and (3) WH and WL are HIGH. The address at A_0 through A_{14} is stored into the address advancement logic and delivered to the RAM core. If the output enable (\overline{OE}) signal is asserted (LOW), data will be available at the data outputs a maximum of 8.5 ns after clock rise. \overline{ADSP} is ignored if \overline{CS} is HIGH.

Burst Sequences

The CY7C178 provides a 2-bit wraparound counter, fed by pins $A_0 - A_1$, that implements the 486 and Pentium processor's address burst sequence (see *Table 1*). Note that the burst sequence depends on the first burst address.

Table 1. Counter Implementation for the Intel Pentium/486 Processor's Sequence

First Address			Fourth Address			
A_{X+1}, A_{x}	A_{X+1}, A_{x}	A_{X+1}, A_{x}	A_{X+1}, A_{x}			
00	01	10	11			
01	00	11	10			
10	11	00	01			
11	10	01	00			

The CY7C179 provides a two-bit wraparound counter, fed by pins $A_0 - A_1$, that implements a linear address burst sequence (see *Table 2*).

Table 2. Counter Implementation for a Linear Sequence

First Address	Second Address	Third Address	Fourth Address			
A_{X+1}, A_{x}	A_{X+1}, A_{x}	A_{X+1}, A_{X}	A_{X+1}, A_{x}			
00	01	10	11			
01	10	11	00			
10	11	00	01			
11	00	01	10			

Application Example

Figure 1 shows a 256-Kbyte secondary cache for the Pentium microprocessor using four CY7C178 cache RAMs.

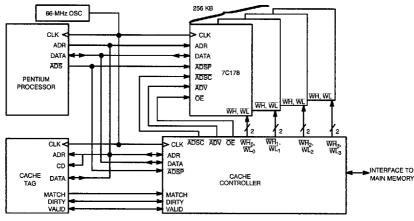


Figure 1. Cache Using Four CY7C178s



Pin Definitions

Signal Name	Туре	# of Pins	Description
V_{CC}	Input	1	+5V Power
V_{CCQ}	Input	4	+5V or 3.3V (Outputs)
GND	Input	1	Ground
V _{SSQ}	Input	4	Ground (Outputs)
CLK	Input	1	Clock
$A_{14} - A_0$	Input	15	Address
ADSP	Input	1	Address Strobe from Processor
ADSC	Input	1 .	Address Strobe from Cache Controller
WH	Input	1	Write Enable - High Byte
WL	Input	1	Write Enable - Low Byte
ADV	Input	1	Advance
ŌĒ	Input	1	Output Enable
CS	Input	1	Chip Select
DQ ₁₅ -DQ ₀	Input/Output	16	Regular Data
DP ₁ -DP ₀	Input/Output	2	Parity Data

Pin Desc	при	0112					
Signal			Signal	710	B 1.0		
Name	I/O	Description	Name	I/O	Description		
Input Sig			WH	I	Write signal for the high-order half of the RAM array. This signal is sampled by the rising edge of		
CLK	I	Clock signal. It is used to capture the address, the data to be written, and the following control signals: ADSP, ADSC, CS, WH, WL, and ADV. It is also used to advance the on-chip auto-address-increment logic (when the appropriate control signals have been set).			CLK. If WH is sampled as LOW, i.e., asserted, the control logic will perform a self-timed write of DQ ₁₅ – DQ ₈ and DP ₁ from the on-chip data register into the selected RAM location. There is one exception to this. If ADSP, WH, and CS are asserted (LOW) at the rising edge of CLK, the write		
A ₁₄ -A ₀	I	Fifteen address lines used to select one of 32K locations. They are captured in an on-chip register on the rising edge of CLK if ADSP or ADSC is			signal, \overrightarrow{WH} , is ignored. Note that \overrightarrow{ADSP} has no effect on \overrightarrow{WH} if \overrightarrow{CS} is HIGH.		
		LOW. The rising edge of the clock also loads the lower two address lines, $A_1 - A_0$, into the on-chip auto-address-increment logic if \overline{ADSP} or \overline{ADSC} is LOW.	<u>WL</u>	1	Write signal for the low-order half of the RAM array. This signal is sampled by the rising edge of CLK. If WL is sampled as LOW, i.e., asserted, the control logic will perform a self-timed write of DQ7 – DQ0 and DP0 from the on-chip data register		
ADSP	I	Address strobe from processor. This signal is sampled at the rising edge of CLK. When this input and/or \overline{ADSC} is asserted, $A_0 - A_{14}$ will be captured in the on-chip address register. It also allows the lower two address bits to be loaded into the			into the selected RAM location. There is one exception to this. If \overrightarrow{ADSP} , \overrightarrow{WL} , and \overrightarrow{CS} are asserted (LOW) at the rising edge of CLK, the write signal, \overrightarrow{WL} , is ignored. Note that \overrightarrow{ADSP} has no effect of \overrightarrow{WL} if \overrightarrow{CS} is HIGH.		
		on-chip auto-address-increment logic. If both ADSP and ADSC are asserted at the rising edge of CLK, only ADSP will be recognized. The ADSP input should be connected to the ADS output of the processor. ADSP is ignored when CS is HIGH.	ADV	I	Advance. This signal is sampled by the rising edge of CLK. When it is asserted, it automatically increments the 2-bit on-chip auto-address-increment counter. In the CY7C179, the address will be incremented linearly. In the CY7C178, the address		
ADSC	I	Address strobe from cache controller. This signal is sampled at the rising edge of CLK. When this input and/or \overline{ADSP} is asserted, $A_0 - A_{14}$ will be captured in the on-chip address register. It also allows the			will be incremented according to the Pentium/486 burst sequence. This signal is ignored if ADSP or ADSC is asserted concurrently with CS. Note that ADSP has no effect on ADV if CS is HIGH.		
		lower two address bits to be loaded into the on- chip auto-address-increment logic. The ADSC in- put should <i>not</i> be connected to the ADS output of the processor.	CS	I	Chip select. This signal is sampled by the rising edge of CLK. If CS is HIGH and ADSC is LOW, the SRAM is deselected. If CS is LOW and ADSC or ADSP is LOW, a new address is captured by the address register. If CS is HIGH, ADSP is ignored.		



Pin Descriptions (continued)

Signal Name	I/O	Description
ŌE	I	Output enable. This signal is an asynchronous input that controls the direction of the data I/O pins. If \overrightarrow{OE} is asserted (LOW), the data pins are outputs, and the SRAM can be read (as long as \overrightarrow{CS} was asserted when it was sampled at the beginning of the cycle). If \overrightarrow{OE} is deasserted (HIGH), the data I/O pins will be three-stated, functioning as inputs, and the SRAM can be written.

Bidirectional Signals

DQ₁₅-DQ₀ I/O Sixteen bidirectional data I/O lines. DQ₁₅ - DQ₈ are inputs to and outputs from the high-order half of the RAM array, while DQ7 - DQ0 are inputs to and outputs from the low-order half of the RAM array. As inputs, they feed into an on-chip data register that is triggered by the rising edge of CLK. As outputs, they carry the data read from the selected location in the RAM array. The direction of the data pins is controlled by \overline{OE} : when \overline{OE} is high, the data pins are three-stated and can be used as inputs; when \overline{OE} is low, the data pins are driven by the output buffers and are outputs. $DQ_{15} - DQ_{8}$ and $DQ_{7} - DQ_{0}$ are also three-stated when \overline{WH} and \overline{WL} , respectively, is sampled LOW at clock

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)
Storage Temperature $\ldots $ $-65^{\circ}C$ to $+150^{\circ}C$
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage on $V_{\mbox{\footnotesize{CC}}}$ Relative to GND $\dots-0.5V$ to $+7.0V$
DC Voltage Applied to Outputs in High Z State $^{[2]}$
DC Input Voltage $^{[2]}$ $\dots \dots -0.5V$ to V_{CC} + $0.5V$
Current into Outputs (LOW)

Signal Name	I/O	Description
DP ₁ -DP ₀	I/O	Two bidirectional data I/O lines. These operate in exactly the same manner as $DQ_{15} - DQ_{0}$, but are named differently because their primary purpose is to store parity bits, while the DQ_{5} 'primary purpose is to store ordinary data bits. DP_{1} is an input to and an output from the high-order half of the RAM array, while DP_{0} is an input to and an output from the lower-order half of the RAM array.

Static Discharge Voltage	>2001V
Latch-Up Current	>200 mA

Operating Range

Range	Ambient Temperature ^[3]	v_{cc}	v_{ccq}
Com'l	0°C to +70°C	5V ± 5%	3.0V to V _{CC}
Mil	-55°C to +125°C	5V ± 5%	5V ± 5%

Electrical Characteristics Over the Operating Range^[4]

			7C178-8 7C179-8					7C178-12 7C179-12	
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Min.	Max.	Unit
V_{OH}	Output HIGH Voltage	$V_{\rm CC}$ = Min., $I_{\rm OH}$ = -4.0 mA	2,4	V_{CCQ}	2.4	V_{CCQ}	2.4	V _{CCQ}	V
V_{OL}	Output LOW Voltage	$V_{\rm CC}$ = Min, $I_{\rm OL}$ = 8.0 mA		0.4		0.4		: 0.4	V
V_{IH}	Input HIGH Voltage		2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	V
V_{IL}	Input LOW Voltage ^[2]		-0.3	0.8	-0.3	0.8	-0.3	0.8	V
I _X	Input Load Current	$GND \le V_I \le V_{CC}$	-1	1	-1	1	-1	1	μА
I_{OZ}	Output Leakage Current	$\begin{array}{l} \text{GND} \leq V_{I} \leq V_{CC,} \\ \text{Output Disabled} \end{array}$	-5	5	-5	5	-5	5	μΑ

- Minimum voltage equals -2.0V for pulse durations of less than 20 ns. 4. See the last page for Group A subgroup testing information.
- TA is the "instant on" case temperature.



Electrical Characteristics Over the Operating Range (continued)^[4]

	7C178-8 7C179-8					7C178-10 7C179-10		7C178-12 7C179-12			
Parameter	Description	Test Condition	ıs	Min.	Max.	Min.	Max.	Min.	Max.	Unit	
Ios	Output Short Circuit Current ^[5]	V _{CC} =Max., V _{OUT} =GND			-300		-300		-300	mA	
I _{CC}	V _{CC} Operating Supply Current	V _{CC} =Max., Iout=0mA.	Com'l		225		210		190	mA	
		$f = f_{MAX} = 1/t_{RC}$	Mil						270		
I _{SB1}	Automatic CE Power- Down Current-TTL Inputs		Com'l		50	·	40		30	mA	
		$V_{IN} \leq V_{IL},$ $f = f_{MAX}$	Mil				1717		50		
I _{SB2}	Automatic CE Power- Down Current-	$\begin{array}{l} \text{Max. V}_{\text{CC}}, \overline{\text{CS}} \geq \\ \text{V}_{\text{CC}} - 0.3\text{V}, \text{V}_{\text{IN}} \geq \end{array}$	Com'l		20		20		20	mA	
	CMOS Inputs	$V_{CC} - 0.3V \text{ or } V_{IN} \le 0.3V, f = 0^{[6]}$	Mil						20		

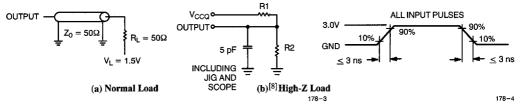
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Capacitance[7]

Parameter	Description	Test Conditions	Max.	Unit	
C _{IN} : Addresses	Input Capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = 5.0$ V	Com'l	4.5	pF
		$V_{\rm CC} = 5.0 V$	Mil	6	
C _{IN} : Other Inputs	7	1	Com'l	5	pF
			Mil	8	
C _{OUT}	Output Capacitance	7	Com'l	8	pF
			Mil	10	

Shaded areas contain advanced information

AC Test Loads and Waveforms



Notes:

- Not more than one output should be shortened at one time. Duration
 of the short circuit should not exceed 30 seconds.
- 6. Inputs are disabled, clock signal allowed to run at speed.
- Tested initially and after any design or process changes that may affect these parameters.
- 8. Resistor values for V_{CCQ}=5V are: R1=481 Ω and R2=255 Ω Resistor values for V_{CCQ}=3.3V are R1=1179 Ω and R2=868 Ω



Switching Characteristics Over the Operating Range[9]

		7C178-8 7C179-8		7C178-10 7C179-10		7C178-12 7C179-12		
Parameter	Description		Max.	Min.	Max.	Min.	Max.	Unit
tCYC	Clock Cycle Time	12.5		15		20	I	ns
t _{CH}	Clock HIGH	5	1	6		8		ns
t _{CL}	Clock LOW	5		6		8		ns
t _{AS}	Address Set-Up Before CLK Rise	2.5		2.5		2.5		ns
t _{AH}	Address Hold After CLK Rise	0.5		0.5		0.5		ns
t _{CDV}	Data Output Valid After CLK Rise		8.5		10		12	ns
t _{DOH}	Data Output Hold After CLK Rise	3		3		3		ns
t _{ADS}	ADSP, ADSC Set-Up Before CLK Rise	2.5		2.5		2.5		ns
t _{ADSH}	ADSP, ADSC Hold After CLK Rise	0.5		0.5		0.5		ns
twes	WH, WL Set-Up Before CLK Rise	2.5		2.5		2.5	,	ns
tweH	WH, WL Hold After CLK Rise	0.5		0.5		0.5		ns
t _{ADVS}	ADV Set-Up Before CLK Rise	2.5		2.5		2.5		ns
t _{ADVH}	ADV Hold After CLK Rise	0.5		0.5		0.5		ns
t _{DS}	Data Input Set-Up Before CLK Rise	2.5		2.5		2.5		ns
t _{DH}	Data Input Hold After CLK Rise	0.5		0.5		0.5		ns
t _{CSS}	Chip Select Set-Up	2.5		2.5		2.5		ns
t _{CSH}	Chip Select Hold After CLK Rise	0.5		0.5		0.5		ns
tcsoz	Chip Select Sampled to Output High Z ^[10]	2	6	2	6	2	7	ns
t _{EOZ}	OE HIGH to Output High Z ^[10]	2	6	2	6	2	7	ns
t _{EOV}	OE LOW to Output Valid		5		5		6	ns
tweoz	WH or WL Sampled LOW to Output High Z ^[10, 11]		5		6		7	ns
tweov	WH or WL Sampled HIGH to Output Valid ^[11]		8.5		10		12	ns

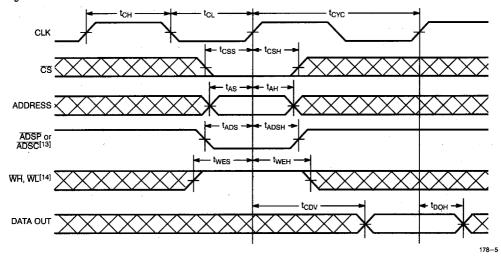
- Notes:

 9. Unless otherwise noted, test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and load capacitance. Shown in Figure (a) and (b) of AC Test Loads.
- 10. t_{CSOZ} , t_{EOZ} , and t_{WEOZ} are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured \pm 500 mV from steady state voltage.
- 11. At any given voltage and temperature, twEOZ min. is less than twEOV

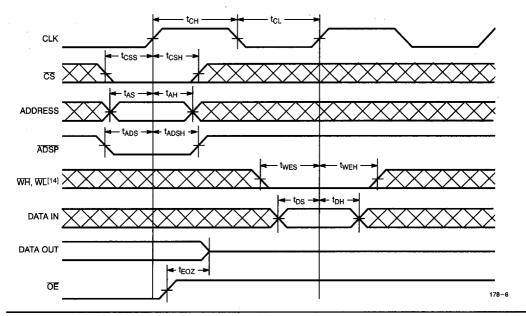


Switching Waveforms

Single Read^[12]



Single Write Timing: Write Initiated by ADSP

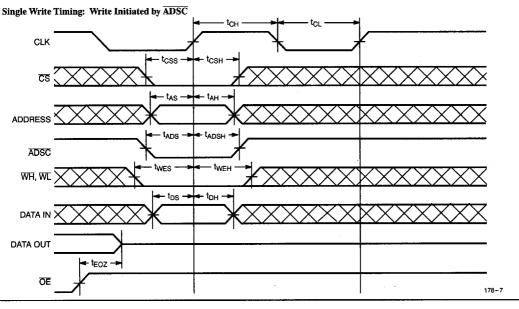


Notes: 12. OE is LOW throughout this operation.

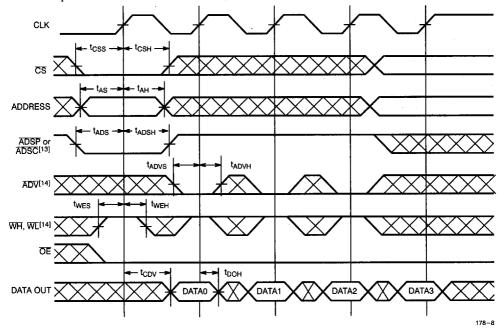
13. If ADSP is asserted while CS is HIGH, ADSP will be ignored.

14. ADSP has no effect on ADV, WH, and WL if CS is HIGH.



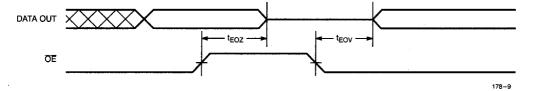


Burst Read Sequence with Four Accesses

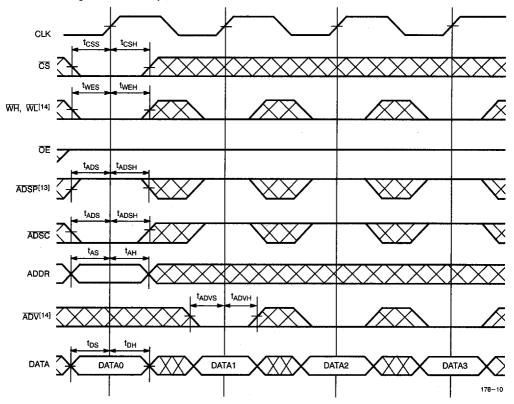




Output (Controlled by \overline{OE})

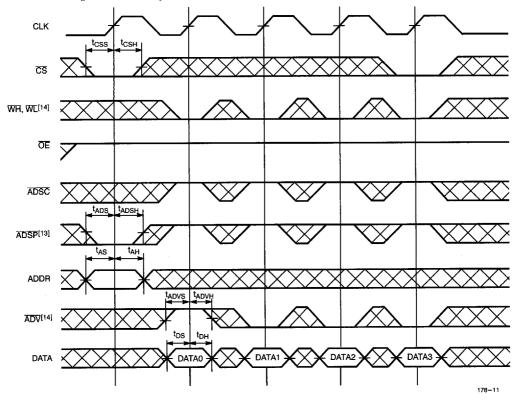


Write Burst Timing: Write Initiated by ADSC

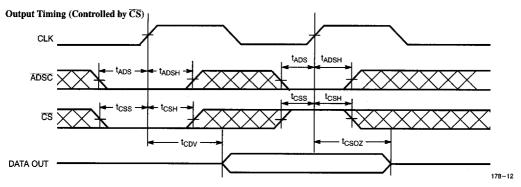


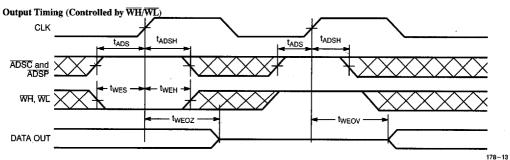


Write Burst Timing: Write Initiated by ADSP









Truth Table

Input							
CS	ADSP	ADSC	ADV	WH or WL	CLK	Address	Operation
Н	L	Н	Н	Н	L→H	Same address as previous cycle	ADSP ignored, read cycle
Н	L	Н	L	Н	L→H	Incremented burst address	ADSP ignored, read cycle in burst sequence
Н	L	H	Н	L	L→H	Same address as previous cycle	ADSP ignored, write cycle
Н	L	Н	L	L	L→H	Incremented burst address	ADSP ignored, write cycle in burst sequence
H	X	L	X	X	L→H	N/A	Chip deselected
L	L	X	X	X	L→H	External	Read cycle, begin burst
L ·	H	L	X	Н	L→H	External	Read cycle, begin burst
L	Н	L	X	L	L→H	External	Write cycle, begin burst
X	Н	Н	L	L	L→H	Incremented burst address	Write cycle, in burst sequence
Х	Н	Н	L	Н	L→H	Incremented burst address	Read cycle, in burst sequence
Х	н	Н	Н	L	L→H	Same address as previous cycle	Write cycle
X	Н	Н	Н	Н	L→H	Same address as previous cycle	Read cycle



Ordering Information

Speed (ns) Ordering Code		Package Name	Package Type	Operating Range	
8	CY7C178-8JC J69 52-Lead Plastic Leaded Chip Carrier		Commercial		
	CY7C178-8NC	TBD -	52-Lead Plastic Quad Flatpack		
10	CY7C178-10JC J69 52-Lead Plastic Leaded Chip		52-Lead Plastic Leaded Chip Carrier	Commercial	
	CY7C178-10NC	TBD	52-Lead Plastic Quad Flatpack		
12	CY7C178-12JC J69 52-Lead		52-Lead Plastic Leaded Chip Carrier	Commercial	
	CY7C178-10NC	TBD	52-Lead Plastic Quad Flatpack		
	CY7C178-12YMB	Y59	52-Pin Ceramic Leaded Chip Carrier	Military	

Speed (ns) Ordering Code		Package Name	Package Type	Operating Range	
8	CY7C179-8JC	J69	52-Lead Plastic Leaded Chip Carrier	Commercial	
	CY7C179-8NC	TBD	52-Lead Plastic Quad Flatpack		
10	CY7C179-10JC	J69	52-Lead Plastic Leaded Chip Carrier	Commercial	
	CY7C179-10NC	TBD	52-Lead Plastic Quad Flatpack		
12	CY7C179-12JC	J69	52-Lead Plastic Leaded Chip Carrier	Commercial	
	CY7C179-12NC	TBD	52-Lead Plastic Quad Flatpack		
	CY7C179-12YMB	Y59	52-Pin Ceramic Leaded Chip Carrier	Military	

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